

<b>Notice of References Cited</b>		Application/Control No. 10/075,193	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner Yennhu B. Huynh	Art Unit 2813	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,376,874 B1	04-2002	Kim, Hyeon-Soo	257/306
X	B	US-5,418,180	05-1995	Brown, Kris K.	438/398
X	C	US-6,046,093	04-2000	DeBoer et al.	438/398
X	D	US-5,661,064	08-1997	Figura et al.	438/396
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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